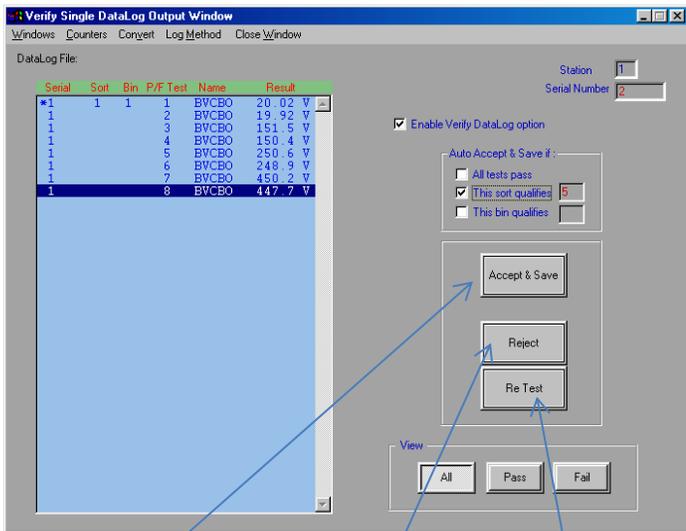




## VERIFY DATA AND SERIALIZATION TO BE SAVED WHILE TESTING SEMICONDUCTORS

When testing semiconductors, the engineer may desire to have complete control over the contents of the Data and the Serial Number of the parts that are being saved into the Data Log file, The Lorlin® Impact Series Tests offer a “Verify Log” Window that should be used in this case.



Accept & Save Data

Reject Data

Retest the Part

When parts are being run through the Lorlin Test Systems® Hi-Rel software, test data from the pre- and post- treatment of a part, typically Mil-Spec, can be compared, Pass/Fail criteria can be stipulated. This is commonly used in applications such as burn-in, scanning, or high/low/ambient temperature testing.

Serialization control of the data log file is critical in this instance, as it is the only way to reference a specific part for the software to perform a comparison of two Data Log files. The Lorlin® test software is set up to perform the user selected comparisons offering Delta parameter data.

Lorlin's Verify Single Data Log Window gives the engineer the opportunity to manually test each part, then determine whether or not the current test run should be saved, the test should be re-run, or the part should be rejected. Throughout this process, the Serial Number value is controlled by the operator, and the Impact software will only increment/change it when the operator indicates it is OK to do so.

For additional information, please contact Lorlin Test Systems, Inc.

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